



3-TERMINAL POSITIVE VOLTAGE REGULATOR

FEATURES

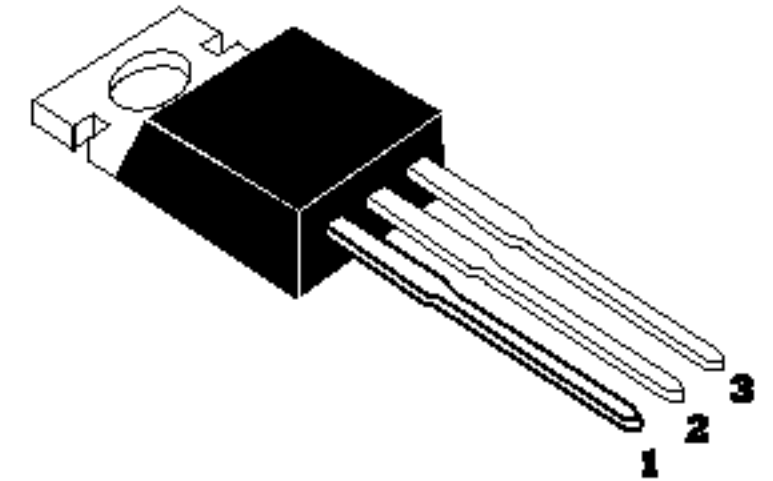
- *Output current In Excess Of 1A
- *Fixed output voltage of 5V available
- *Thermal overload shutdown protection
- *Short circuit current limiting
- *Output transistor SOA protection

ABSOLUTE MAXIMUM RATINGS

(Operating temperature range applies unless otherwise specified)

Characteristic	Symbol	Rating	Unit
Input voltage	V_I	35	V
Output Current	I_O	1.5	A
Power Dissipation	P_D	internally Limited	mW
Operating Junction Temperature Range	T_{OPR}	-20~150	$^{\circ}C$
Storage Temperature Range	T_{STG}	-55~150	$^{\circ}C$

Package: TO-220



PIN:	1	2	3
STYLE			
NO.1	I	G	O

ELECTRICAL CHARACTERISTICS at $T_{amb}=25^{\circ}C$

($V_I=10V, I_O=0.5A, 0^{\circ}C < T_j < 125^{\circ}C, C_I=0.33\mu F, C_O=0.1\mu F$, unless otherwise specified)(Note 1)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Conditions
Output Voltage	V_O	4.8	5	5.2	V	$T_j=25^{\circ}C$
Output Voltage	V_O	4.75		5.25	V	$8V \leq V_I \leq 20V, I_O=5mA-1.0A$ $PD < 15W$
Load Regulation	ΔV_O		1.3	100	mV	$T_j=25^{\circ}C, I_O=5mA-1.5A$
Load Regulation	ΔV_O		0.15	50	mV	$T_j=25^{\circ}C, I_O=0.25A-0.75A$
Line Regulation	ΔV_O		5	100	mV	$7V \leq V_I \leq 25V, T_j=25^{\circ}C$
Line Regulation	ΔV_O		1.3	50	mV	$8V \leq V_I \leq 12V, T_j=25^{\circ}C$
Quiescent Current	I_q		3.2	8	mA	$T_j=25^{\circ}C$
Quiescent Current Change	ΔI_q			1.3	mA	$8V \leq V_I \leq 25V$
Quiescent Current Change	ΔI_q			0.5	mA	$5mA \leq I_O \leq 1.0A$
Output Noise Voltage	V_N		10		μV	$10Hz \leq f \leq 100kHz$
Temperature coefficient of V_O	$\Delta V_O / \Delta T$		-0.30		mV/ $^{\circ}C$	
Ripple Rejection	RR		68		dB	$8V \leq V_I \leq 18V, f=120Hz, T_j=25^{\circ}C$
Peak Output Current	I_{pk}		2.2		A	$T_j=25^{\circ}C$
Short-Circuit Current	I_{sc}		200		mA	$V_I=35V, T_j=25^{\circ}C$
Dropout Voltage	V_D		2.0		V	$T_j=25^{\circ}C, I_O=1A$

Note 1: The maximum steady state usable output current is dependent on input voltage, heat sinking, lead length of the package and copper patten of PCB. The data above represent pulse test conditions with junction temperatures specified at the initiation of test.